



Glass Composition Analysis

Major Constituents

Wavelength Dispersive X-ray Fluorescence (WD-XRF) can measure major and minor glass constituents.

Example: WD-XRF: Selected Compounds

SRM 93a borosilicate glass (wt%)		
	Measured	Actual
B ₂ O ₃	12.00	12.56
Na ₂ O	4.17	3.98
MgO	0.005	0.005
Al ₂ O ₃	2.35	2.28
SiO ₂	81.3	80.8
Cl	0.078	0.060
K ₂ O	0.016	0.014
CaO	0.016	0.01
TiO ₂	0.016	0.014
ZrO ₂	0.040	0.042

Trace Elements & Ultra-Trace Impurities

Inductively Coupled Plasma Mass Spectrometry (ICP-MS) measures low concentrations and trace level concentrations with high accuracy. ICP-MS. High Resolution- ICP-MS enables the analysis of impurities in quartz glass/sand down to ultra-trace levels.

Example: ICP-MS: Selected Elements

NIST 611 Trace Elements in Glass (ppm wt)		
	Measured	Actual
B	465	485
Na	10.2 wt%	10.2 wt%
Mg	483	465
Al	1.05 wt%	1.04 wt%
K	452	486
Fe	474	457
Co	413	405
Mo	359	377
Eu	477	461
Ta	391	377

Example: HR-ICP-MS: Selected Elements

	Limit of detection in quartz glass/sand (ppm wt)
Al	0.2
Ca	0.2
Ce	0.02
Cr	0.05
Cu	0.02
Fe	0.1
Ge	0.02
K	0.2
Li	0.02
Mg	0.05
Mn	0.02
Mo	0.02
Ni	0.02
Na	0.2
Ti	0.02
W	0.05
Zn	0.2
Zr	0.02

Inclusions & Small Area

Laser Ablation ICP-MS (LA-ICP-MS) measures areas as small as 4 µm. Sampling depth ~1 µm.

Example: LA-ICP-MS: Selected Elements

NIST 611 Trace Elements in Glass (ppm wt)		
	Measured	Actual
B	474	485
Na	9.9 wt%	10.2 wt%
Mg	570	465
Al	1.10 wt%	1.04 wt%
K	483	486
Fe	456	457
Co	407	405
Mo	409	377
Eu	471	461
Ta	440	377

For more information about our glass analysis services, please visit eag.com/industry/glass/